







ISO/IEC17025 Accredited Lab.

Report No: EMC1411102-01 File reference No: 2014-12-09

Applicant:

Product: Bluetooth Earphone

Brand Name:

Model No: BTH-040, BTH-042,BTH-026

Test Standards: ETSI EN 300 328 V 1.8.1 (2012-06)

Test result:

The EMC testing has been performed on the submitted samples

and found in compliance with council EMC Directive 2004/108/EC and R & TTE Directive 1999/5/EC

Approved By

Teny Tang

Terry Tang

EMC Manager

Dated: December 09, 2014

Results appearing herein relate only to the sample tested

The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TESTING LABORATORIES

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Date: 2014-12-09



Special Statement:

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

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The testing quality system of our laboratory meet with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

CNAS-LAB Code: L2292

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of testing Laboratories.

FCC-Registration No.: 899988

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 899988.

IC-Registration No.: IC5205A-02

The EMC Laboratory has been registered and fully described in a report filed with the (IC) Industry Canada. The acceptance letter from the IC is maintained in our files. Registration IC No.: 5205A-02.

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Test Report Conclusion

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1. General Information

1.1 Notes

The test results of this report relate exclusively to the test item specified in 1.5. The TIMEWAY Lab does not assume Responsibility for any conclusions and generalizations drawn from the test results with regard to other specimens or samples of the type of the equipment represented by the test item. The test report may only be reproduced or published in full. Reproduction or publication of extracts from the report requires the prior written approval of the TIMEWAY Lab.

1.2 Testing Laboratory

SHENZHEN TIMEWAY TESTING LABORATORIES

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Site on File With the Federal Communications and Commission – United States

Registration Number: 899988

For 3m & 10 m OATS

Site Listed with Industry Canada of Ottawa, Canada

Registration Number: IC: 5205A-02

For 3m & 10 m OATS

1.3 Test Data

Date of Receipt of Application: Nov 18, 2014 Date of Receipt of Test Item: Nov 18, 2014 Date of Test: Nov 18, 2014~ Dec 05, 2014

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1.4 Description of EUT

EUT Type:	Bluetooth Earphone	
Applicant:		
Manufacturer:		
Equipment type:	Bluetooth 2 4G	
Bluetooth Version:	3.0+EDR	
Modulation Type (Technology):	GFSK, Л/4DQPSK, 8DPSK	for Bluetooth
Operating Frequency Range:	2.402GHz - 2.480GHz	
Modulation used by the equipment.	FHSS	
Maximum e.r.i.p:	2.86dBm	
	GFSK	842kHz
Maximum OCB	Л/4DQPSK	1136kHz
Adaptive Mode:	Adaptive/non-adaptive equipment:	Adaptive Equipment without the possibility to switch to a non-adaptive mode
	LBT Base DAA:	Yes
	Non-LBT Base DAA:	No
	Number of transmit chain:	1
	Number of receive chain:	1
	Channel Occupancy Time:	0.84ms (worse case)
Antenna Gain:	Antenna Type:	Integral Antenna
	Antenna Gain:	0 dBi
Operating voltage:	Normal:	3.7V
	Lowest:	3.1V
	Highest:	4.3V
Operating temperature	Normal:	25℃
	Lowest:	-20℃
	Highest:	55℃

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1.5 Setting of test system

Setting Value				
EUT type:	Bluetooth 2.4G			
	Mode	Data Rate		
	GFSK	1Mbps		
	Л/4DQPSK,	2Mbps		
	8DPSK	3Mbps		
EUT frequency configurable:	Yes			
Test channel-Low:	2402MHz (GFS)	K, Л/4DQPSK, 8DPSK)		
Test channel-Middle:	2441MHz (GFS)	K, Л/4DQPSK, 8DPSK)		
Test channel-High:	2480MHz (GFS)	K, Л/4DQPSK, 8DPSK)		
Adaptive:	Yes			
With TPC function:	No			
Number of the antenna:	1			
Number of transmission chains:	1			
Beam forming:	No	No		
Operating frequency range:	2400MHz~2483.5	MHz		
Maximum beam forming gain:	N.A			
Antenna gain:	0dBi			

1.6 Test Standards

ETSI EN 300 328 v 1.8.1 (2012-06)

Electromagnetic compatibility and Radio spectrum Matters(ERM);

Wideband Transmission systems;

Data transmission equipment operating in the 2.4GHz ISM band and using spread spectrum modulation techniques; Harmonized EN covering essential requirements under article 3.2 of the R&TTE Directive

Note: All radiated measurements were made in all three orthogonal planes. The values reported are the maximum values.

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1.7 Configuration of The EUT

The EUT was configured according to CISPR16. All interface ports were connected to the appropriate peripherals. All peripherals and cables are listed below.

A. EUT

Device	Manufacturer	Model
Bluetooth Earphone	Richen Industrial Co., Ltd.	BTH-040,
		BTH-042

B. Internal Devices

Device	Manufacturer	Model
N/A		

C. Peripherals

Device	Manufacturer	Model	Cable
N/A			

D. EUT Exercise

The EUT (Transmitter) was operated in the engineering mode to fix the Tx frequency that was for the purpose of the measurements.

1.8 EUT Modifications

No modification by SHENZHEN TIMEWAY TESTING LABORATORIES

1.9 Tests or Witness Test Engineering

Printing Name: Terry Tang

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2. Technical Test

2.1 Summary of Test Results

No deviations from the technical specification(s) were ascertained in the course of the tests Performed			
Final Verdict:	Pass		
(Only "Passed" if all Measurements are "Passed")			

2.2 Test Report

Test Report Reference

List of Measurements							
Parameter to be measured	Clause	Result					
Transmitte	Transmitter Parameters						
RF output power	Clause 4.3.1.1	Pass					
Duty Cycle, Tx-sequence, Tx-gap	Clause 4.3.1.2	N/A					
Dwell Time, Minimum Frequency Occupation and Hopping Sequence	Clause 4.3.1.3	Pass					
Hopping Frequency Separation	Clause 4.3.1.4	Pass					
Medium Utilisation (MU) Factpr	Clause 4.3.1.5	N/A					
Adaptivity (Adaptive Frequency Hopping)	Clause 4.3.1.6	N/A					
Occupied Channel Bandwidth	Clause 4.3.1.7	Pass					
Transmitter unwanted emissions in the out-of-band domain	Clause 4.3.1.8	Pass					
Transmitter unwanted emissions in the spurious domain	Clause 4.3.1.9	Pass					
Receiver	Parameters						
Receiver Spurious Emissions	Clause 4.3.1.10	Pass					
Receiver Blocking	Clause 4.3.1.11	N/A					

Note: The clause numbers are referenced to ETSI EN 300 328 V 1.8.1(2012-06)

Note: N/A= Not applicable. Because these requirements do not apply for equipment with a maximum declared RF Output power of less than 10 dBm e.i.r.p. or for equipment when operating in a mode where the RF Output power is less than 10 dBm e.i.r.p. For the EUT, the RF output power less than 10dBm.

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Clause 4.3.1.1 RF output Power (Conducted)

Test Method according to clause 5.3.2.2.1

GFSK Mode

	Transmitter Power (dBm) EIRP					
Test Conditions	T _{nom} (25℃)	T _{min} (-20°C)		T _{max} (55°C)		
	DC3.7V	DC3.1V	DC4.3V	DC3.1V	DC4.3V	
Low Freq.2402MHz	2.36	2.42	2.42	2.40	2.37	
Mid Freq.2441MHz	2.62	2.59	2.65	2.56	2.63	
High Freq.2480MHz	2.86	2.73	2.82	2.69	2.77	

Л/4DQPSK Mode

	Transmitter Power (dBm) EIRP					
Test Conditions	T_{nom} (25°C)	T _{min} (-20°C)		T_{max} (55°C)		
	DC3.7V	DC3.1V	DC4.3V	DC3.1V	DC4.3V	
Low Freq.2402MHz	1.12	1.19	1.20	1.40	1.31	
Mid Freq.2441MHz	1.20	1.16	1.23	1.33	1.37	
High Freq.2480MHz	1.38	1.36	1.32	1.46	1.49	

8DPSK Mode

	Transmitter Power (dBm) EIRP					
Test Conditions	T _{nom} (25°C)	T _{min} (-20°C)		T _{max} (55℃)		
	DC3.7V	DC3.1V	DC4.3V	DC3.1V	DC4.3V	
Low Freq.2402MHz	1.14	1.07	1.02	1.03	1.09	
Mid Freq.2441MHz	1.08	1.13	1.08	1.06	1.16	
High Freq.2480MHz	1.36	1.31	1.22	1.31	1.28	

Limits: Clause 4.3.1.1.2

The maximum RF output power for adaptive Frequency Hopping equipment shall be equal to or less than 20 dBm.

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Clause 4.3.1.3 Dwell Time, Minimum Frequency Occupation and Hopping Sequence

For Adaptive frequency hopping system

Test method according to Clause 5.3.4.2.1

GFSK Mode

Gran	viouc							
	Dwell Time							
Mode	Mode Number of Number of transmission in a period (Channel Number *						Result	Limit
	Hopping		0.4	4sec)		transmissions	(ms)	(ms)
	Channel	Period	Sweep Time	Times in a	Times in a	Time (ms)		
		(Sec)	(Sec)	sweep	period			
DH1	79	31.6	4	40	316.0	0.481	152.00	400
DH3	79	31.6	4	22	173.8	1.784	310.06	400
DH5	79	31.6	4	16	126.4	3.006	379.96	400

Л/4DQPSK Mode

	Dwell Time										
Mode	Number of	Number o	of transmission in	a period (Channe	Length of	Result	Limit				
	Hopping		0.4	4sec)		transmissions	(ms)	(ms)			
	Channel	Period	Sweep Time	Times in a	Times in a	Time (ms)					
		(Sec)	(Sec)	sweep	period						
DH1	79	31.6	4	40	316.0	0.461	145.68	400			
DH3	79	31.6	4	21	165.9	1.703	282.53	400			
DH5	79	31.6	4	15	118.5	2.966	351.47	400			

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GFSK Mode

	Minimum Frequency Occupation Time									
Mode	Number of Hopping Channel	Number of transmission in a period of 4* Dwell * number of hopping channel	Length of transmissions Time (ms)	Result (ms)	Minimum Limit (ms)					
DH1	79	2	0.481	0.962	0.481					
DH3	79	3	1.784	5.352	1.784					
DH5	79	3	3.006	9.018	3.006					

Л/4DOPSK Mode

	Minimum Frequency Occupation Time									
	Will ill Trieque licy Occupation Time									
Mode	Number of	Number of transmission in a period of 4* Dwell *	Result	Minimum						
	Hopping	number of hopping channel	transmissions	(ms)	Limit					
	Channel		Time (ms)		(ms)					
DH1	79	2	0.461	1.383	0.461					
DH3	79	3	1.703	5.109	1.703					
DH5	79	3	2.966	8.898	2.966					

Note: Note: GFSK and Π/4DQPSK Mode was the worse case

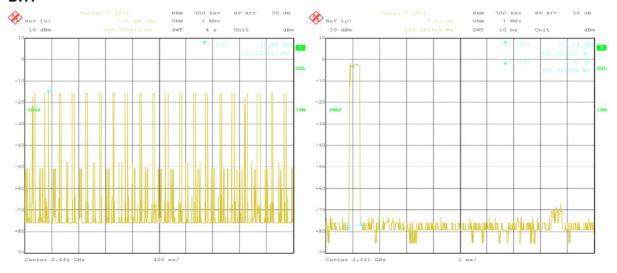
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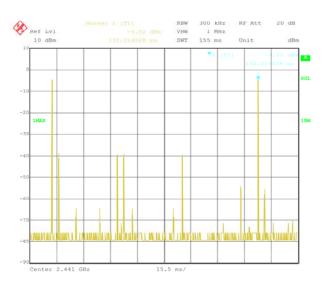
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GFSK Mode



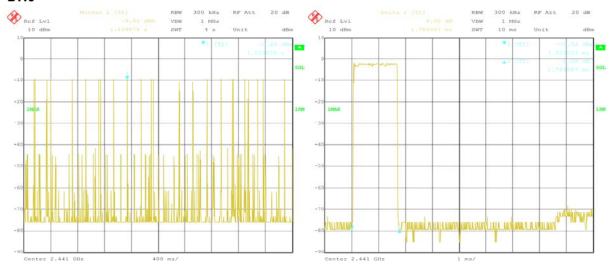


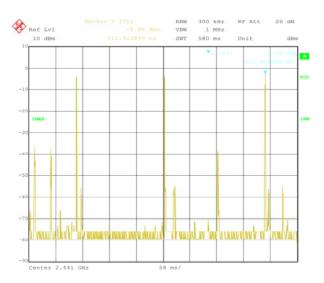
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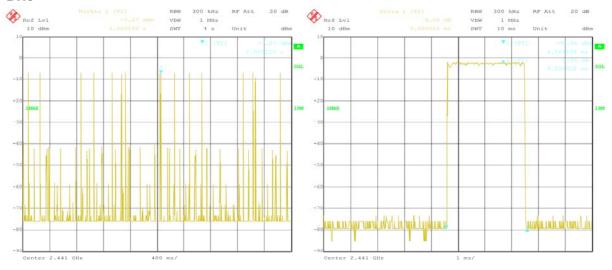


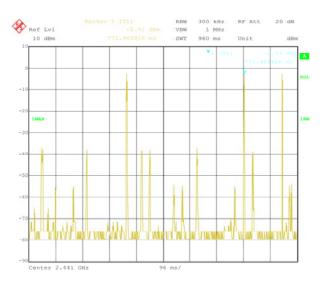
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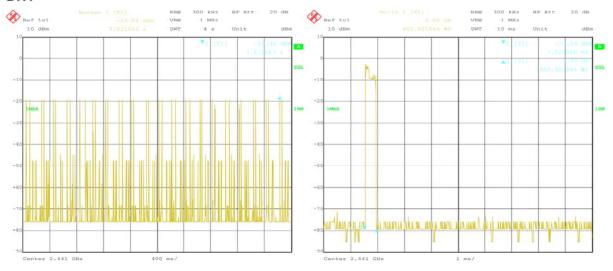
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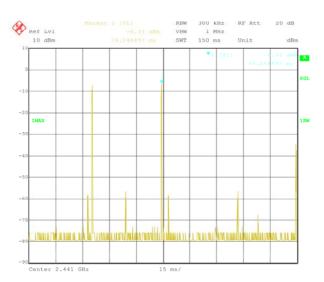
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Л/4DQPSK Mode



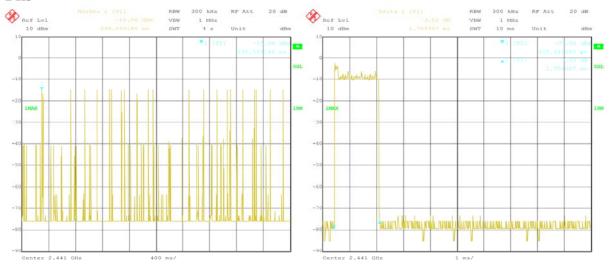


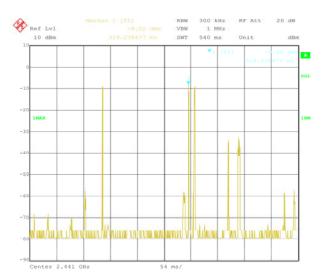
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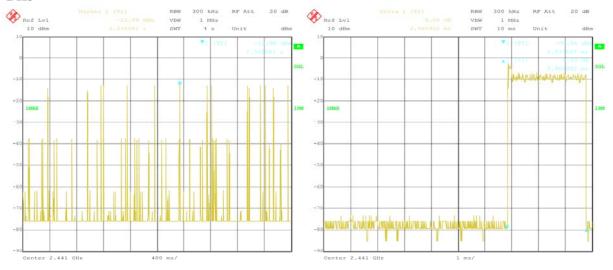


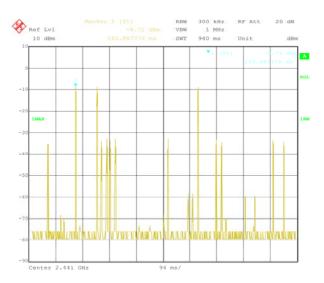
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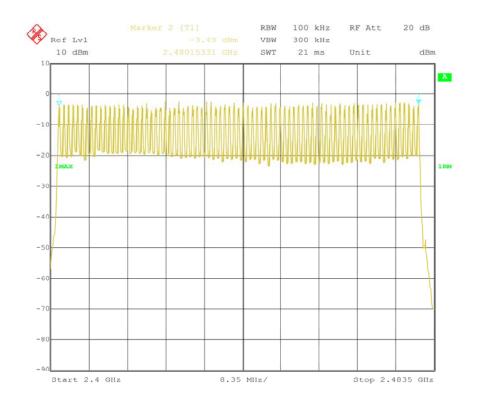
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Hopping sequence

GFSK

EUT	Bluetooth Speaker		Model		BTH-040, BTH-042		
Mode	Hopping On		Input Voltage		DC3.7V		
Temperature	24 deg. C,		Humidity		56% RH		
Operating Frequency		Number of hopping cha	nnels	Lin	nit	it Pass/ Fail	
2402-2480MHz		79		≥ 1	.5	Pass	



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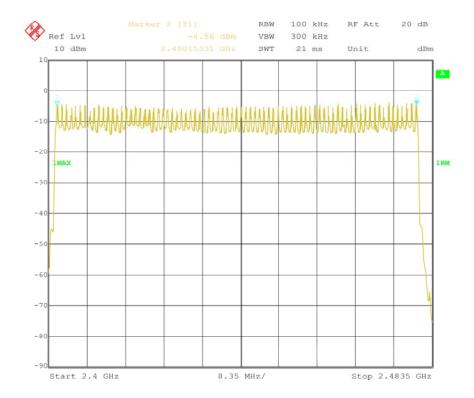
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Л/4DQPSK Mode

EUT	Bluetooth Speaker		Model		BTH-040, BTH-042	
Mode	Hopping On		Input Voltage		DC3.7V	
Temperature	24 deg. C,		Humidity		56% RH	
Operating Frequency		Number of hopping cha	annels	Lin	nit	Pass/ Fail
2402-2480MHz		79		≥ 1	.5	Pass



Note: Note: GFSK and $\Pi/4DQPSK$ Mode was the worse case

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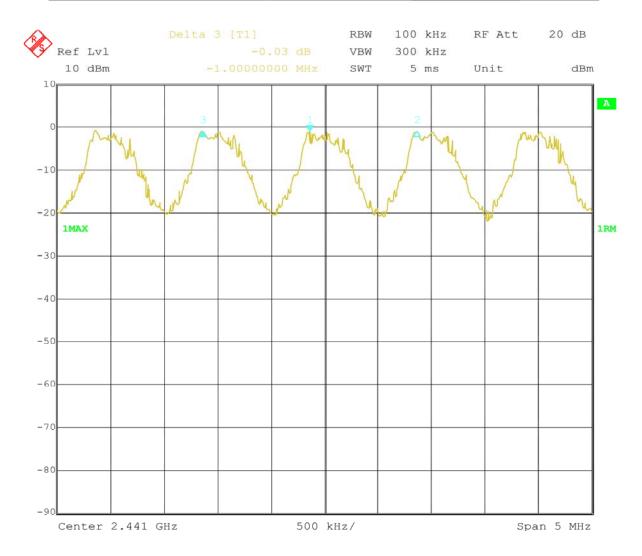


Clause 4.3.1.4 Hopping Frequency Separation

Test method according to Clause 5.3.5.2.1.2

GFSK Mode

EUT		Bluetooth	Speaker	Model		BTH-040, BTH-042		
Mode		Hoppin	g On	n Input Voltage De		C3.7V		
Temperature		24 deg	g. C,	Humidi	ity	56% RH		
Channel	Ch	annel Frequency (MHz)	Carrier Frequ Separatio	•	Limit		Pass/ Fail	
Middle	iddle 2441		1.002MH	Iz	≥100kHz		Pass	



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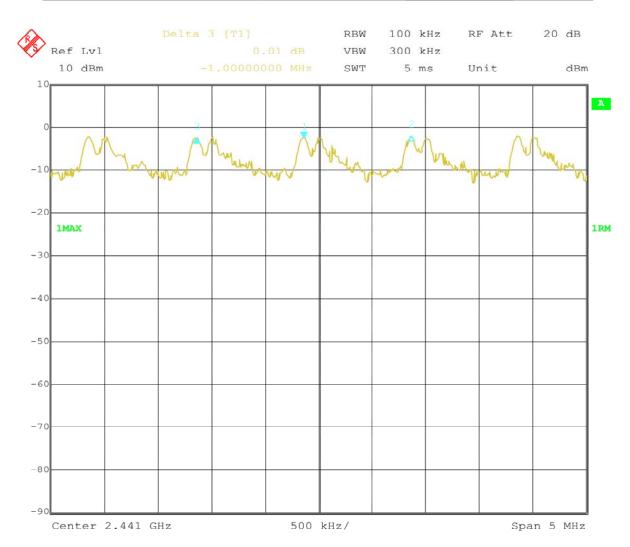
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Л/4DQPSK Mode

EUT		Bluetooth	Speaker	Model		BTH-040, BTH-0	
Mode		Hoppin	g On	Input Voltage DC		C3.7V	
Temperature		24 deg	g. C,	Humidi	ity	56% RH	
Channel	Ch	annel Frequency	Carrier Frequ	-	Lin	nit	Pass/ Fail
		(MHz)	Separatio	n			
Middle	Middle 2441		1.002MH	[z	≥100kHz		Pass



Note: Note: GFSK and JI/4DQPSK Mode was the worse case

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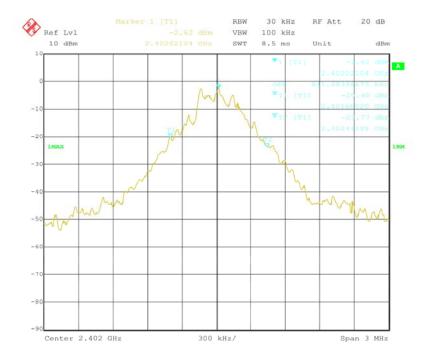
Clause 4.3.1.7 Occupied Channel Bandwidth

Test method according to Clause 5.3.8.2.1

GFSK Mode

EU'	EUT Blueto		ooth Speaker		Model	BTH-04	0, BTH-042
Mode		Но	Hopping On		put Voltage	DC3.7V	
Temperature		24	4 deg. C,		Humidity	56	% RH
Channel	Channel Frequency (MHz)		99% Channel Bandwidth (kHz)		Measured F (MH		Limit(MHz)
Low		2402	842		2401.:	598	≥2400
High	igh 2480		830		2480.4	438	≤2483.5
Result: Pa	ass						

Low Channel



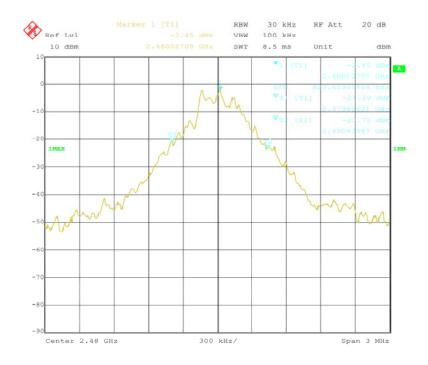
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High Channel



Л/4DQPSK Mode

EU'	EUT Blueto		ooth Speaker		Model	BTH-04	0, BTH-042		
Mode		Но	pping On	In	Input Voltage DC3.7V		C3.7V		
Temperature		24	l deg. C,		Humidity	56	% RH		
Channel	Channel Frequency (MHz)		99% Channel Bandwidth (kHz)		Measured F (MH		Limit(MHz)		
Low		2402	1136		2401.4	442 ≥2400			
High	2480		1124		2480.	594	≤2483.5		
Result: Pa	Result: Pass								

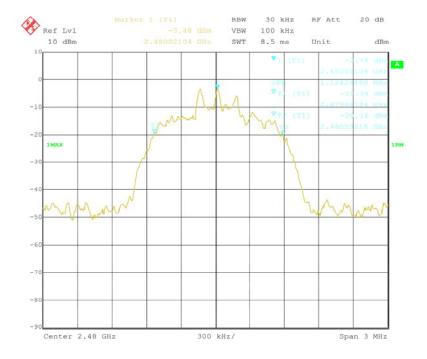
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Low Channel



High Channel



Note: Note: GFSK and II/4DQPSK Mode was the worse case

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Clause 4.3.1.8 Transmitter unwanted emissions in the out-of-band domain

Test method according to Clause 5.3.9.2.1

EUT	Bluetooth Speaker	Model	BTH-040, BTH-042	
Mode	Hopping On	Input Voltage	DC3.7V	
Temperature	24 deg. C,	Humidity	56% RH	

GFSK Mode

Chan	nel	2402	2MHz	2480	MHz				
Freque	ency	(OCB:0.	842MHz)	(OCB: 0.83MHz)					
Test Cor	ndition	OOB Emis	sion (MHz)	OOB Emis	sion (MHz)				
		2399.158-2400	2398.316-2399.158	2483.5-2484.33	2484.33-2485.16				
		Max. Power	Max. Power	Max. Power	Max. Power				
		(dBm/MHz	(dBm/MHz	(dBm/MHz	(dBm/MHz				
T _{nor} 25°C	V _{nor} (V)	-44.33	-50.76	-45.34	-51.33				
T _{min} -20°C	$V_{min}(V)$	V _{min} (V) -43.75 -50.59		-45.28	-51.27				
T _{max} 55℃	$V_{min}(V)$	-44.12	-50.56	-45.51	-51.50				
T _{min} -20°C	$V_{\text{max}}(V)$	-43.82	-50.32	-45.36	-51.22				
T _{max} 55℃	$V_{\text{max}}(V)$	-44.02	-50.28	-45.45	-51.31				
Limit (dBm)	-10	-20	-10	-20				
Pass/	Fail	Pass	Pass	Pass	Pass				

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Л/4DQPSK Mode

Chan	nel	2402	2MHz	2480MHz		
Freque			136MHz)	(OCB: 1.142MHz)		
Test Cor	ndition	OOB Emis	ssion (MHz)	OOB Emis	ssion (MHz)	
		2398.864-2400	2397.728-2398.864	2483.5-2484.642	2484.642-2485.784	
		Max. Power	Max. Power	Max. Power	Max. Power	
		(dBm/MHz)	(dBm/MHz)	(dBm/MHz)	(dBm/MHz)	
T _{nor} 25°C	V _{nor} (V)	-49.77	-52.12	-49.76	-54.21	
T _{min} -20°C	$V_{min}(V)$	-49.08	-52.18	-49.35	-54.39	
T _{max} 50°C	V _{min} (V)	-49.12	-52.35	-49.41	-54.51	
T _{min} -20°C	$V_{\text{max}}(V)$	-48.92	-51.65	-49.29	-54.07	
T _{max} 55 ℃	$V_{max}(V)$	-48.76	-52.03	-49.16	-54.24	
Limit (dBm)	-10	-20	-10	-20	
Pass/	Fail	Pass	Pass	Pass Pass		

Note: Note: GFSK and $\Pi/4DQPSK$ Mode was the worse case

Date: 2014-12-09



Clause 4.3.1.9 Transmitter unwanted emissions in the spurious domain

(Radiated)

Transmitter Operating

Note:

- 1. Measurements were done on low & high channels, but depicting the worst case are submitted in the report.
- 2. The spurious emissions were done with different settings, using the relevant pre-amplifiers for the relevant frequency ranges.
- 3. The test frequency range is from 30M-12.75G and please see clause 5.3.10.2.2 of EN 300 328 for the test method.

Lowest Frequency (2402MHz)			Highest Frequency (2480MHz)			
f(MHz)	Band-Width (kHz)	Level (dBm)	f(MHz)	Band-Width (kHz)	Level (dBm)	
NF			NF			
NF			NF		_	
Measurement Uncertainty		±6dB				

Limits Clause 4.3.1.9.2

Table 1: Transmitter limits for spurious emissions

Frequency range	Maximum power, e.r.p. (≤ 1 GHz)	Bandwidth
	e.i.r.p. (> 1 GHz)	
30 MHz to 47 MHz	-36 dBm	100 kHz
47 MHz to 74 MHz	-54 dBm	100 kHz
74 MHz to 87,5 MHz	-36 dBm	100 kHz
87,5 MHz to 118 MHz	-54 dBm	100 kHz
118 MHz to 174 MHz	-36 dBm	100 kHz
174 MHz to 230 MHz	-54 dBm	100 kHz
230 MHz to 470 MHz	-36 dBm	100 kHz
470 MHz to 862 MHz	-54 dBm	100 kHz
862 MHz to 1 GHz	-36 dBm	100 kHz
1 GHz to 12,75 GHz	-30 dBm	1 MHz

Note: GFSK was the worse case

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Clause 4.3.1.10 Receiver Spurious Emissions (Radiated)

Note:

- 1. Measurements were done on low & high channels, but depicting the worst case are submitted in the report.
- 2. The receiver spurious emissions were done with different settings, using the relevant and pre-amplifiers for the relevant frequency ranges.
- 3. The test frequency range is from 30M-12.75G and please see clause 5.3.11.2.2 of EN 300 328 for the test method.

Low Channel			High Channel			
f(MHz)	Band-Width (kHz)	Level (dBm)	f(MHz)	Band-Width (kHz)	Level (dBm)	
NF			NF	-		
NF			NF	-	-	
Measurement Uncertainty		±6dB				

Limits Clause 4.3.1.10.2

Table 2: Spurious emission limits for receivers

	Frequency range	Maximum power e.r.p. (≤ 1 GHz) e.i.r.p. (> 1 GHz)	Measurement bandwidth		
	30 MHz to 1 GHz	-57 dBm	100 kHz		
Γ	1 GHz to 12,75 GHz	-47 dBm	1 MHz		

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3.0 **Product Labelling**

CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



Mark Location: Rear enclosure

Date: 2014-12-09



4.0 Spurious Radiated emission test view





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5.0 **Photos of EUT**

Outside view



Date: 2014-12-09



Outside view





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Inside view





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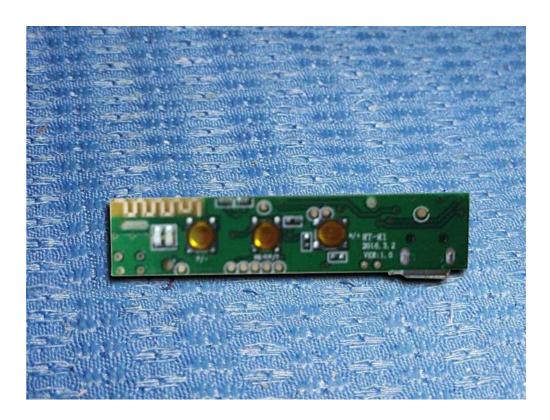
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Inside view



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Inside view



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Inside view



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6.0	Test Equipments						
Instrument Type	Manufacturer	Model	Serial No.	Date of Cal.	Due Date		
ESPI Test Receiver	ROHDE&SCHWARZ	ESPI 3	100379	2014-08-21	2015-08-20		
Absorbing Clamp	ROHDE&SCHWARZ	MDS-21	100126	2014-08-22	2015-08-21		
TWO Line-V-NETW	ROHDE&SCHWARZ	EZH3-Z5	100294	2014-08-22	2015-08-21		
TWO Line-V-NETW	ROHDE&SCHWARZ	EZH3-Z5	100253	2014-08-23	2015-08-22		
Ultra Broadband ANT	ROHDE&SCHWARZ	HL562	100157	2014-08-22	2015-08-21		
ESDV Test Receiver	ROHDE&SCHWARZ	ESDV	100008	2014-08-21	2015-08-20		
4-WIRE ISN	ROHDE&SCHWARZ	ENY 41	830663/044	2014-08-22	2015-08-21		
GG ENY22 Double 2-Wire ISN	ROHDE&SCHWARZ	ENY22	83066/016	2014-08-22	2015-08-21		
Impuls-Begrenzer	ROHDE&SCHWARZ	ESH3-Z2	100281	2014-08-21	2015-08-20		
System Controller	СТ	SC100	-	2014-08-23	2015-08-22		
Oscillator	KENWOOD	AG-203D	3070002	2014-08-21	2015-08-20		
Spectrum Analyzer	HAMEG	HM5012	-	2014-08-22	2015-08-21		
Power Supply	LW	APS1502	ı	2014-08-21	2015-08-20		
5K VA AC Power Source	California Instruments	5001iX	56060	2014-08-22	2015-08-21		
CDN	EM TEST	CDN M2/M3	-	2014-08-22	2015-08-21		
Attenuation	EM TEST	ATT6/75	-	2014-08-22	2015-08-21		
Resistance	EM TEST	R100	-	2014-08-21	2015-08-20		
Electromagnetic Injection Clamp	LITTHI	EM101	35708	2014-08-24	2015-08-23		
Inductive Components	EM TEST	MC2630	-	2014-08-21	2015-08-20		
Antenna	EM TEST	MS100		2014-08-23	2015-08-22		
Signal Generator	ROHDE&SCHWARZ	SMT03	100029	2014-08-23	2015-08-22		
Power Amplifier	AR	150W1000	300999	2014-08-22	2015-08-21		

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Field probe	Holaday	HI-6005	105152	2014-08-21	2015-08-20
Bilog Antenna	Chase	CBL6111C	2576	2014-08-21	2015-08-20
Loop Antenna	EMCO	6502	00042960	2014-08-22	2015-08-21
ESPI Test Receiver	ROHDE&SCHWARZ	ESI26	838786/013	2014-08-21	2015-08-20
3m OATS	I		N/A	2014-08-25	2015-08-24
Vector Signal Generator	AGILENT	E4438C	MY49070163	2014.01.19	2015.01.18
Splitter	Mini-Circuits	ZAP-50W	NN256400424	2014.01.19	2015.01.18
Directional Coupler	AGILENT	87300C	MY44300299	2014.01.19	2015.01.18
vector Signal Generator	AGILENT	E4438C	US44271917	2014.01.19	2015.01.18
4 Ch.Simultaneous Sampling 14 Bits 2 MS/s	AGILENT	U2531A	TW54063507	2014.01.19	2015.01.18
4 Ch.Simultaneous Sampling 14 Bits 2 MS/s	AGILENT	U2531A	TW54063513	2014.01.19	2015.01.18
Splitter	Mini	PS3-7	4463	2014.01.19	2015.01.18
Spectrum	AGILENT	E7405A	US44210471	2014.02.26	2015.02.25
Analyzer					
Attenuator	Resnet	20dB	(n,a)	2014.02.26	2015.02.25
Signal Analyzer	AGILENT	N9010A	MY48030494	2014.01.19	2015.01.18

End of the Report

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